nexperia

Quarterly Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

Based on structural	similarity
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Supplier		User Part Number						
Nexperia B.V.		PESD5V0U1UT						
Name of L	aboratory	Part Description						
		Nexperia DHAM Small Signal Bipolar Protection						
Assembly reliability labs		SMD package						
Based on AEC-Q101 Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113	24 h a					
	PC	Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85%	24 hours 168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	286	21480	0		
# 11		MIL-STD-750-1	-,	200	21100	~		
	HTRB	M1038 Method A						
		Tj = Tjmax, Vr = 100% of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	78	6240	0		
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	86	6880	0		
		JESD22-A102						
" • • • •	AC Autoclave	Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)	0.5.1		6000			
# A3 alt	Autociave	Plessure = 203 kPa (29.7 psia)	96 hours	86	6880	0		
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = $85 ^{\circ}$ C, RH = 85% , VR = 80% of						
# A2 alt	Temperature Reverse Bias		1000 hours	86	6880	0		
		MIL-STD-750 Method 1037				-		
	IOL	ton = toff, devices powered to insure ΔT_j =						
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	28	840	0		
	SD							
# C10	Solderability	J-STD-002		36	360	0		

[1]The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
	Small Signal Bipolar Protection	6240	0	0.68	1.47E+09

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